IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Public	ations/Services Standards Conferences Careers/Jobs					
Help FAQ Terms IE	EE Peer Review Quick Links "Se					
Welcome to IEEE Xplore						
O- Home	Your search matched 653 of 966109 documents.					
O- What Can	A maximum of 500 results are displayed, 15 to a page, sorted by Relevance in descending order.					
Access?	You may refine your search by editing the current search expression or entering a new one the text box. Then click Search Again .					
O- Log-out						
Tables of Contents	((reliability)and (test)) and(monitoring)					
O- Journals & Magazines	Results: Journal or Magazine = JNL Conference = CNF Standard = STD					
O- Conference Proceedings						
O- Standards	1 Reliability monitoring and screening issues with ultrathin gate dielect					
***************************************	devices					
Search	Abadeer, W.W.; Device and Materials Reliability, IEEE Transactions on , Volume: 1 Issue: 1 , Ma					
O- By Author	2001					
O- Basic	Page(s): 60 -68					
O- Advanced	1 495(5): 55 55					
Member Services	[Abstract] [PDF Full-Text (216 KB)] IEEE JNL					
O- Join IEEE	[Machael] [Machael Machael Mac					
O- Establish IEEE Web Account	2 A test methodology to monitor and predict early life reliability failure					
	mechanisms					
O- Access the IEEE Member	Conrad, T.R.; Mielnik, R.J.; Musolino, L.S.;					
Digital Library	Reliability Physics Symposium 1988. 26th Annual Proceedings., International, 1					
Print Format	April 1988					
	Page(s): 126 -130					
	[Abstract] [PDF Full-Text (256 KB)] IEEE CNF					
3 An in-process monitor for n-channel MOSFET hot carrier lifetin						
	Mistry, K.R.; Krakauer, D.B.; Doyle, B.S.; Spooner, T.A.; Jackson, D.B.;					
	Reliability Physics Symposium 1992. 30th Annual Proceedings., International, 3					
	March-2 April 1992					
	Page(s): 116 -121					
	[Abstract] [PDF Full-Text (480 KB)] IEEE CNF					

4 Condition monitoring of 11-132 kV cable accessories

Dean, B.;

Ensuring the Reliability of 11-132 kV Cable Accessories (Digest No. 1998/191), Colloquium on , 4 Feb. 1998

Page(s): 5/1 -5/4

[Abstract] [PDF Full-Text (244 KB)] IEE CNF

5 Production implementation of a practical WLR program [wafer level reliability]

Garrard, S.;

Advanced Semiconductor Manufacturing Conference and Workshop. 1994. ASMC Proceedings. IEEE/SEMI, 14-16 Nov. 1994

Page(s): 144 -146

[Abstract] [PDF Full-Text (316 KB)] IEEE CNF

6 Isothermal wafer-level electromigration test for the characterization metal system reliability monitoring

Kuo, C.K.; Yuan, H.C.; Lee, S.C.; Lee, S.Y.; Chu, L.H.; Shiue, R.Y.; Yue, J.T.; VLSI Technology, Systems, and Applications, 2001. Proceedings of Technical Pa 2001 International Symposium on , 18-20 April 2001

Page(s): 275 -278

[Abstract] [PDF Full-Text (256 KB)] IEEE CNF

7 Condition monitoring of HV electrical rotating plant-on-line partial discharge techniques

Brown, A.J.;

Understanding your Condition Monitoring (Ref. No.1999/117), IEE Colloquium o April 1999

Page(s): 1/1 - 1/3

[Abstract] [PDF Full-Text (96 KB)] IEE CNF

8 The practical side of thin dielectric monitoring and characterization

Suehle, J.S.; Messick, C.; Langley, B.;

Integrated Reliability Workshop, 1994. Final Report., 1994 International, 16-19

Page(s): 1 -2

[Abstract] [PDF Full-Text (128 KB)] IEEE CNF

9 New control methods and process monitoring for improving performa of power diodes manufacturing

Galateanu, L.; Bazu, M.; Tibeica, C.; Popa, E.; Nichita, A.; Turtudau, F.; Semiconductor Conference, 2002. CAS 2002 Proceedings. International, Volum 8-12 Oct. 2002

Page(s): 347 -350 vol.2

[Abstract] [PDF Full-Text (471 KB)] IEEE CNF

10 Improvement of high voltage switchgear reliability

Thuries, E.; Ebersohl, G.; Dupraz, J.P.; Chetay, O.; Moncorge, J.P.; Trends in Distribution Switchgear, 1994., Fourth International Conference on , 7 Nov 1994

Page(s): 145 -149

[Abstract] [PDF Full-Text (304 KB)] IEE CNF

11 Demonstrated reliability of plastic-encapsulated microcircuits for micapplications

Sun Man Tam;

Reliability, IEEE Transactions on , Volume: 44 Issue: 1 , March 1995

Page(s): 8 -13

[Abstract] [PDF Full-Text (508 KB)] **IEEE JNL**

12 On-line monitoring of power generating systems

Kotlica, M.U.;

Power Station Maintenance - Profitability Through Reliability, 1998. First IEE/IM
International Conference on (Conf. Publ. No. 452), 30 March-1 April 1998
Page(s): 32 -38

[Abstract] [PDF Full-Text (804 KB)] **IEE CNF**

13 A test vehicle for monitoring and improvement of CMOS reliability performance

Remmerie, G.;

Euro ASIC '90 , 29 May-1 June 1990

Page(s): 444 -448

[Abstract] [PDF Full-Text (376 KB)] IEEE CNF

14 An expert management system for VRLA batteries in remote telecommunications centers

Poulin, J.; Heron, R.; Mailloux, D.;

Telecommunications Energy Conference, 1994. INTELEC '94., 16th Internationa Oct.-3 Nov. 1994

Page(s): 497 -504

[Abstract] [PDF Full-Text (384 KB)] IEEE CNF

15 Investigation of the intrinsic SiO₂ area dependence using TDDB testi

Prendergast, J.; Finucane, N.; Suehle, J.;

Integrated Reliability Workshop Final Report, 1997 IEEE International , 13-16 O 1997

Page(s): 22 -25

[Abstract] [PDF Full-Text (240 KB)] IEEE CNF

1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18 19 20 21 22 23 24 25 26 27 28 32 33 34 [Next]

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search

Join | IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting

No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ| Terms | Back to Top

Copyright © 2003 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publi	cations/Services Standards Conferences Careers/Jobs
	Velcome United States Patent and Trademark Office
Help FAQ Terms I	EEE Peer Review Quick Links × Se
Welconie to IEEE Xplore	Your search matched 583 of 966109 documents.
O- Home	
O- What Can I Access?	A maximum of 500 results are displayed, 15 to a page, sorted by Relevance in descending order. You may refine your search by editing the current search expression or entering a new one the text box.
O- Log-out	Then click Search Again.
Tables of Contents	(self <in> ti)and (test <in> ti) and interrupt Search Again</in></in>
O- Journals & Magazines	Results: Journal or Magazine = JNL Conference = CNF Standard = STD
O- Conference Proceedings	
O- Standards	1 A highly portable, self-stimulating and self-testing reliability test chip ASIC products
Search	Erhart, D.L.; Colunga, T.; Lopez, D.;
	ASIC Conference and Exhibit, 1993. Proceedings., Sixth Annual IEEE Internation
O- By Author O- Basic	Sept1 Oct. 1993
O- Advanced	Page(s): 160 -163
-	
Member Salvices	[Abstract] [PDF Full-Text (452 KB)] IEEE CNF
O- Join IEEE O- Establish IEEE	
Web Account	2 Mixed-signal custom IC control processors incorporating design for
O- Access the	test/self-test
IEEE Member Digital Library	Grout, I.A.; Burge, S.E.; Winsby, A.J.; DSP Chips in Real Time Measurement and Control (Digest No: 1997/301), IEE
Print Format	Colloquium on , 25 Sept. 1997
Oma Lener Enterings	Page(s): 1/1 -1/4
	[Abstract] [PDF Full-Text (388 KB)] IEE CNF
	3 Self-tuning predictive control of a hydraulic test rig Daley, S.; Liu, G.P.;
	Adaptive Controllers in Practice '97 (Digest No: 1997/176), IEE Colloquium on ,
	April 1997
	Page(s): 12/1 -12/3
	[Abstract] [PDF Full-Text (192 KB)] TEE CNE

4 The "Prometeo" test bed: a unidirectional WDM transparent self heali

ring in a field environment

Merli, S.; Arecco, F.; Mariconda, A.; Pozzi, F.; Veghini, F.; Iannone, E.; Integrated Optics and Optical Fibre Communications, 11th International Confere on, and 23rd European Conference on Optical Communications (Conf. Publ. No.: 448), Volume: 3, 22-25 Sept. 1997

Page(s): 247 250 vol 2

Page(s): 347 -350 vol.3

[Abstract] [PDF Full-Text (436 KB)] IEE CNF

5 The development and application of intelligent self test concepts in reconfigurable modular avionic systems

Cooper, R.; Shark, L.K.; Terrell, T.J.;

Systems Design for Testability, IEE Colloquium on , 26 Apr 1995

Page(s): 8/1 -8/5

[Abstract] [PDF Full-Text (228 KB)] **IEE CNF**

6 Incorporating boundary-scan and built-in self-test within a VHDL-bas ASIC design cycle

Findlay, P.; Dickinson, B.; Harriss, M.;

Testing-the Gordian Knot of VLSI Design, IEE Colloquium on , 28 May 1993

Page(s): 3/1 - 3/4

[Abstract] [PDF Full-Text (216 KB)] **IEE CNF**

7 Progress in the long term testing of an all dielectric self supporting cafor power system use

Carlton, G.; Carter, C.N.; Peacock, A.J.;

Electricity Distribution, 1993. CIRED., 12th International Conference on , 17-21 1993

Page(s): 3.16/1 -3.16/4 vol.3

[Abstract] [PDF Full-Text (228 KB)] IEE CNF

8 Self-testing in an electricity meter: new contribution to intelligent metering

Rozman, M.; Jeglic, A.; Jamnik, P.;

Metering Apparatus and Tariffs for Electricity Supply, 1992., Seventh Internation

Conference on , 17-19 Nov 1992

Page(s): 161 -163

[Abstract] [PDF Full-Text (120 KB)] IEE CNF

9 Self-tuning controller design for a nonlinear engine testing dynamom King, P.J.; Burnham, K.J.; James, D.J.G.; Norton, J.; Sharpe, S.R.; Real Control Problems - No Solutions Yet?, IEE Colloquium on , 30 May 1991 Page(s): 2/1 -2/4

[Abstract] [PDF Full-Text (132 KB)] IEE CNF

10 Implementation of a self-tuning controller to the dynamometer torque loop of an engine test cell

King, P.J.; Burnham, K.J.; James, D.J.G.; Norton, J.; Sharpe, S.R.; Control 1991. Control '91., International Conference on , 25-28 Mar 1991 Page(s): 110 -114 vol.1

[Abstract] [PDF Full-Text (228 KB)] IEE CNF

Aging and self-healing in connectors: implications for accelerated telliamson, J.B.P.;

Electrical Contacts, IEE Colloquium on , 4 Apr 1989

Page(s): 2/1

[Abstract] [PDF Full-Text (40 KB)] **IEE CNF**

Automatic self-test provides improved accuracy and user confidence Rudkin, A.M.;

Reliable Electronic Measurements, IEE Colloquium on , 10 Mar 1989

Page(s): 6/1 -6/4

[Abstract] [PDF Full-Text (172 KB)] IEE CNF

13 Propulsion and friction braking diagnostics and self test capabilities Roberts, R.D.;

Main Line Railway Electrification, 1989., International Conference on , 25-28 Se

Page(s): 63 -66

[Abstract] [PDF Full-Text (336 KB)] **IEE CNF**

14 The benefits of built in self test for OEM designers Diamond, P.; Bradford, J.;

Custom VLSI Design and Test, IEE Colloquium on , 31 Oct 1988 Page(s): 8/1 -8/9

[Abstract] [PDF Full-Text (460 KB)] IEE CNF

15 An integrated high-level test synthesis algorithm for built-in self-tes designs

Yang, L.T.; Muzio, J.;

Integrated Circuits and Systems Design, 2001, 14th Symposium on. , 10-15~Se 2001

Page(s): 115 -121

[Abstract] [PDF Full-Text (616 KB)] IEEE CNF

1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18 19 20 21 22 23 24 25 26 27 28 32 33 34 [Next]

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ | Terms | Back to Top

Copyright © 2003 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE Publications/Services Standards Welcome United States Patent and Trademark Office » S€ **Quick Links** FAQ Terms IEEE Peer Review Welcome to IEEE XPIONS Your search matched [0] of [966109] documents. ()- Home You may refine your search by editing the current search expression or entering)- What Can a new one the text box. Then click search Again. I Access? Search Again ((self <in> ti)and (test <in> ti)) and(interrupt) O- Log-out Tables of Contents OR Journals & Magazines Use your browser's back button to return to your original search page. Conference **Proceedings** Results: O- Standards No documents matched your query. Search O- By Author ()- Basic C Advanced Member Services O- Join IEEE Establish IEEE Web Account Access the **IEEE** Member **Digital Library** Print Format

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ | Terms | Back to Top

Copyright © 2003 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Public	attons/Services	Standards Conferen	ces Careers/Jobs		
	Xplore			elcoma nt and Trademark Office	
Help FAQ Terms IE	EE Peer Review	Quick Links		» S€	
Velocite to lease A Colores - Home - What Can I Access? - Log-out Indicac Populate - Journals & Magazines - Conference Proceedings - Standards Statell - By Author - Basic - Advanced	Your search match A maximum of 26 You may refine yo Then click Search ((self)and (test) Results: Journal or Magazin 1 A static fa Putrus, G.A.; Fault Current Page(s): 5/1	results are displayed, 15 ur search by editing the content of the	to a page, sorted by Releva urrent search expression or of CNF Standard = STD and interrupting er, C.B.;	entering a new one the text box.	
O- Join IEEE O- Establish IEEE Web Account O- Access the IEEE Member Digital Library	2 IBM single chip RISC processor (RSC) Moore, C.R.; Balser, D.M.; Muhich, J.S.; East, R.E.; Computer Design: VLSI in Computers and Processors, 1992. ICCD '92. Proceed IEEE 1992 International Conference on , 11-14 Oct. 1992 Page(s): 200 -204				
Print Format	[Abstract]	PDF Full-Text (420	KB)] IEEE CNF		
	arc quenchi Yu Jianjun; G	ng Guo Wenyuan; Gao l ulating Materials, 19	Liangyu;	materials in SF₆ self-er mposium on , 17-20 Sept.	

[Abstract] [PDF Full-Text (192 KB)] **IEEE CNF**

4 An efficient parallel transparent BIST method for multiple embedded memory buffers

Huang, D.C.; Jone, W.B.; Das, S.R.; VLSI Design, 2001. Fourteenth International Conference on , 3-7 Jan. 2001 Page(s): 379 -384

[Abstract] [PDF Full-Text (488 KB)] IEEE CNF

Behaviour of SF₆ high-voltage circuit breakers with different arcextinguishing systems at short-line fault switching

Knoblock, H.; Habedank, U.;

Science, Measurement and Technology, IEE Proceedings- , Volume: 148 Issue:

Nov. 2001

Page(s): 273 -279

[Abstract] [PDF Full-Text (646 KB)] IEE JNL

6 A microcomputer-based speed controller for lift drives

Petrovcic, J.; Strmcnik, S.;

Industry Applications, IEEE Transactions on , Volume: 24 Issue: 3 , May-June

Page(s): 487 -498

[Abstract] [PDF Full-Text (1028 KB)] IEEE JNL

7 Interruption ability of a self extinguishing type gas circuit breaker Arita, H.; Natsui, K.; Tsukushi, M.; Kurosawa, Y.; Hirasawa, K.; Power Delivery, IEEE Transactions on , Volume: 5 Issue: 3 , July 1990

Page(s): 1362 -1369

[Abstract] [PDF Full-Text (556 KB)] IEEE JNL

8 Cathode spot dynamics on pure metals and composite materials in hi current vacuum arcs

Chaly, A.M.; Logatchev, A.A.; Shkol'nik, S.M.;

Plasma Science, IEEE Transactions on , Volume: 25 Issue: 4 , Aug. 1997

Page(s): 564 -570

[Abstract] [PDF Full-Text (176 KB)] IEEE JNL

9 A parallel transparent BIST method for embedded memory arrays by tolerating redundant operations

Huang, D.C.; Jone, W.B.;

Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions

Volume: 21 Issue: 5 , May 2002

Page(s): 617 -628

[Abstract] [PDF Full-Text (352 KB)] **IEEE JNL**

10 New vacuum arc control technology and its application

Niwa, Y.; Nitta, K.; Yokokura, K.; Somei, H.; Kaneko, E.; Power Engineering Society Winter Meeting, 2000. IEEE, Volume: 3, 23-27 Jar

Page(s): 2111 -2116 vol.3

[Abstract] [PDF Full-Text (468 KB)] IEEE CNF

11 Dual processor VHSIC MIL-STD-1750 A computer module

Coulon, K.;

Aerospace and Electronics Conference, 1988. NAECON 1988., Proceedings of th 1988 National , 23-27 May 1988

Page(s): 54 -59 vol.1

[Abstract] [PDF Full-Text (600 KB)] IEEE CNF

Secondary arc current interruption in an unconventional MV distribution and experimental test results

Carrus, A.; Gatta, F.M.; Cinieri, E.;

Properties and Applications of Dielectric Materials, 1991., Proceedings of the 3rd International Conference on , 8-12 July 1991

Page(s): 354 -358 vol.1

[Abstract] [PDF Full-Text (348 KB)] **IEEE CNF**

13 Fault scanner for reconfigurable logic

Shnidman, N.R.; Mangione-Smith, W.H.; Potkonjak, M.;

Advanced Research in VLSI, 1997. Proceedings., Seventeenth Conference on ,

Sept. 1997

Page(s): 238 -255

[Abstract] [PDF Full-Text (912 KB)] IEEE CNF

14 Dynamic fault tolerance in FPGAs via partial reconfiguration

Emmert, J.; Stroud, C.; Skaggs, B.; Abramovici, M.; Field-Programmable Custom Computing Machines, 2000 IEEE Symposium on , April 2000

Page(s): 165 -174

[Abstract] [PDF Full-Text (972 KB)] IEEE CNF

Self excitation of induction motors compensated by permanently connected capacitors and recommendations for IEEE Std 141-1993

Ermis, M.; Calir, Z.; Cadirci, I.; Zenginobuz, G.; Tezcan, H.;

Industry Applications Conference, 2000. Conference Record of the 2000 IEEE,

Volume: 5, 8-12 Oct. 2000 Page(s): 3135 -3145 vol.5

[Abstract] [PDF Full-Text (808 KB)] IEEE CNF

1 <u>2</u> [Next]

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online Publications | Help. | FAQ| Terms | Back to Top

Copyright © 2003 IEEE - All rights reserved